

# G0 Analysis Update

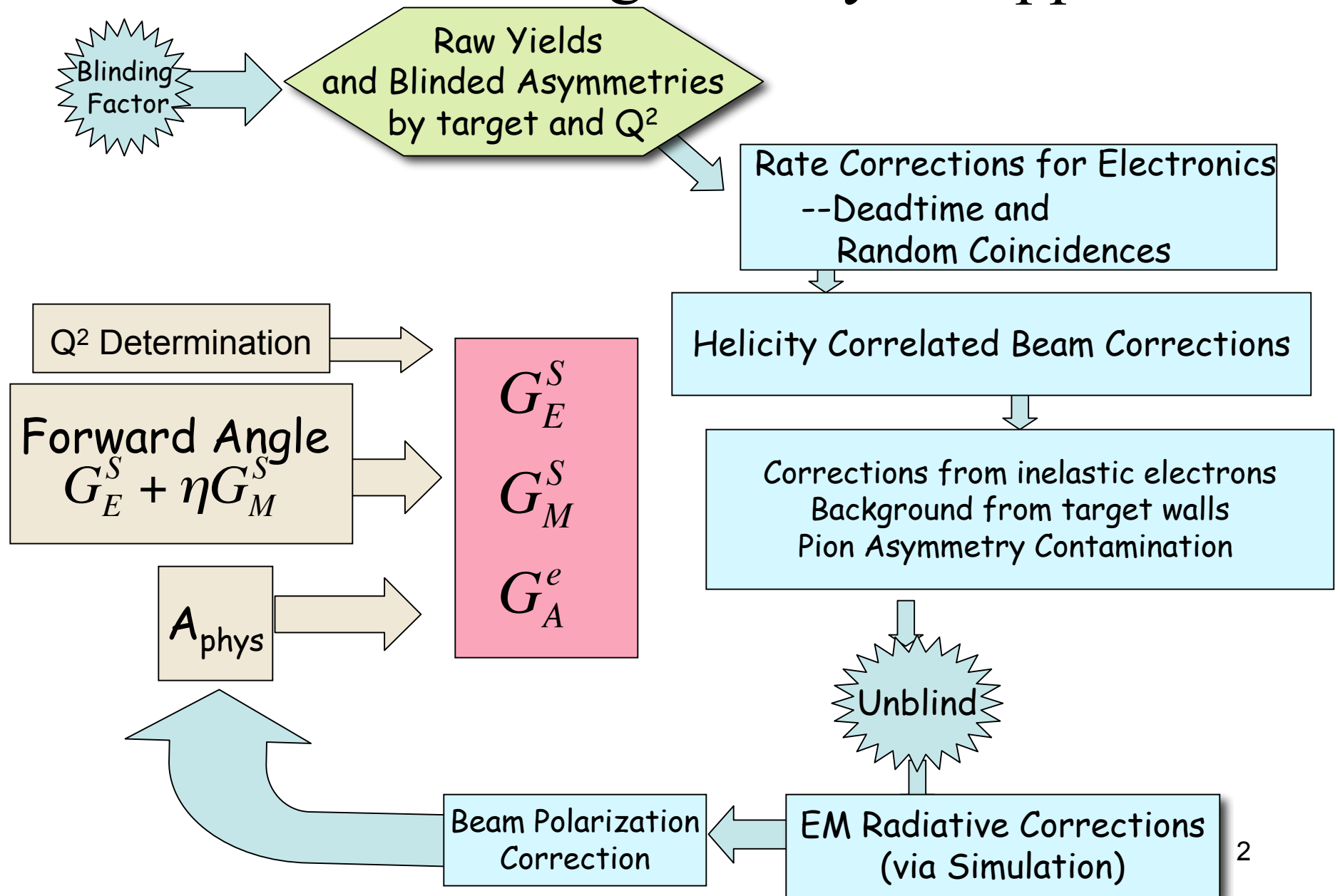
John Schaub

NMSU

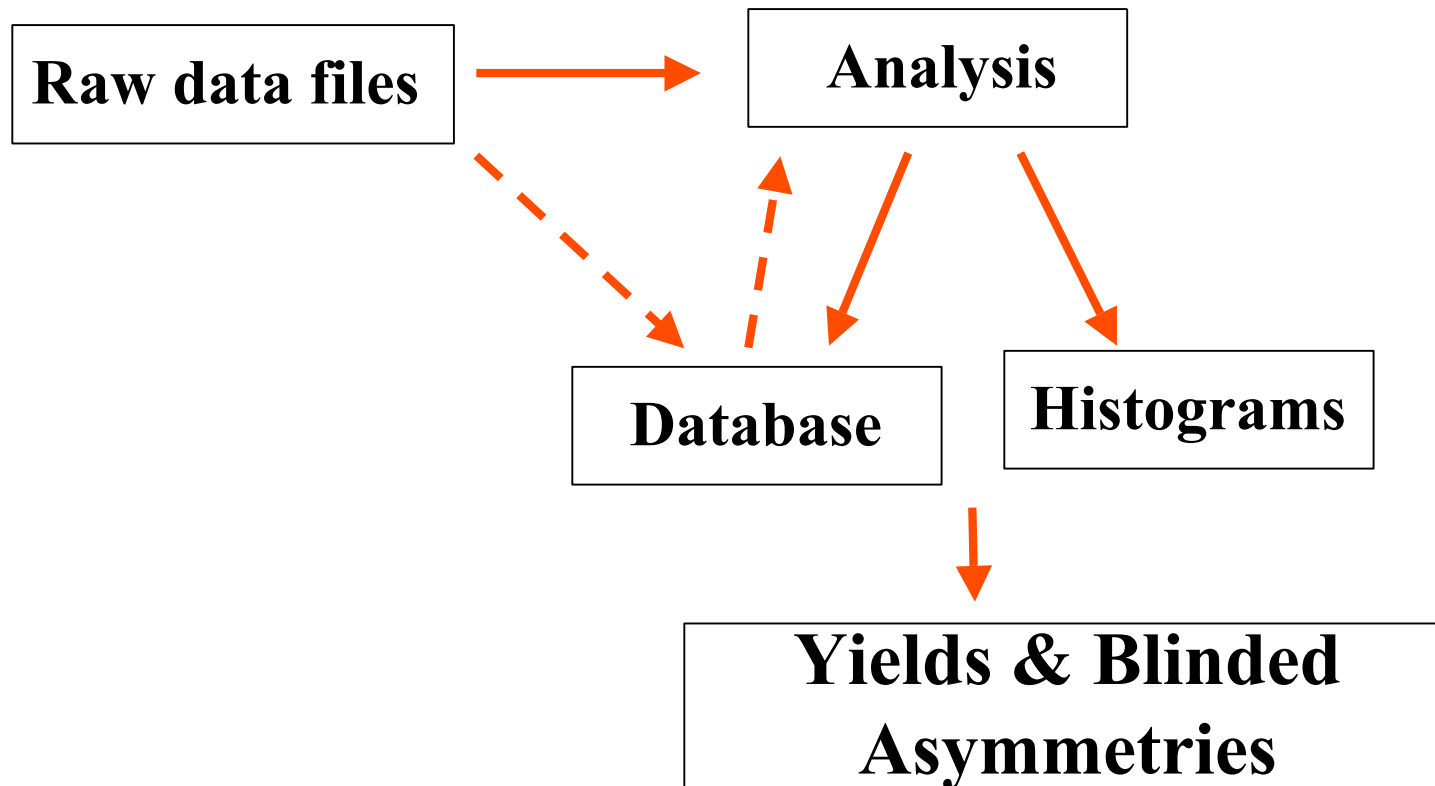
Hall C Meeting, JLab

January, 2008

# G0 Backward Angle Analysis Approach



# G0 Analyzer



# Asymmetry Analysis

(Four Analysis Passes)

## Beam calibrations

- **Pass 1:**

- **Uncorrected yields and blinded asymmetries**



- **Pass 2:**

- **Scaler counting correction**



- **Pass 3:**

- **Electronic corrections  
(deadtime, randoms,  
contamination)**



- **Pass 4:**

- **Linear regression correction**

Pass 1

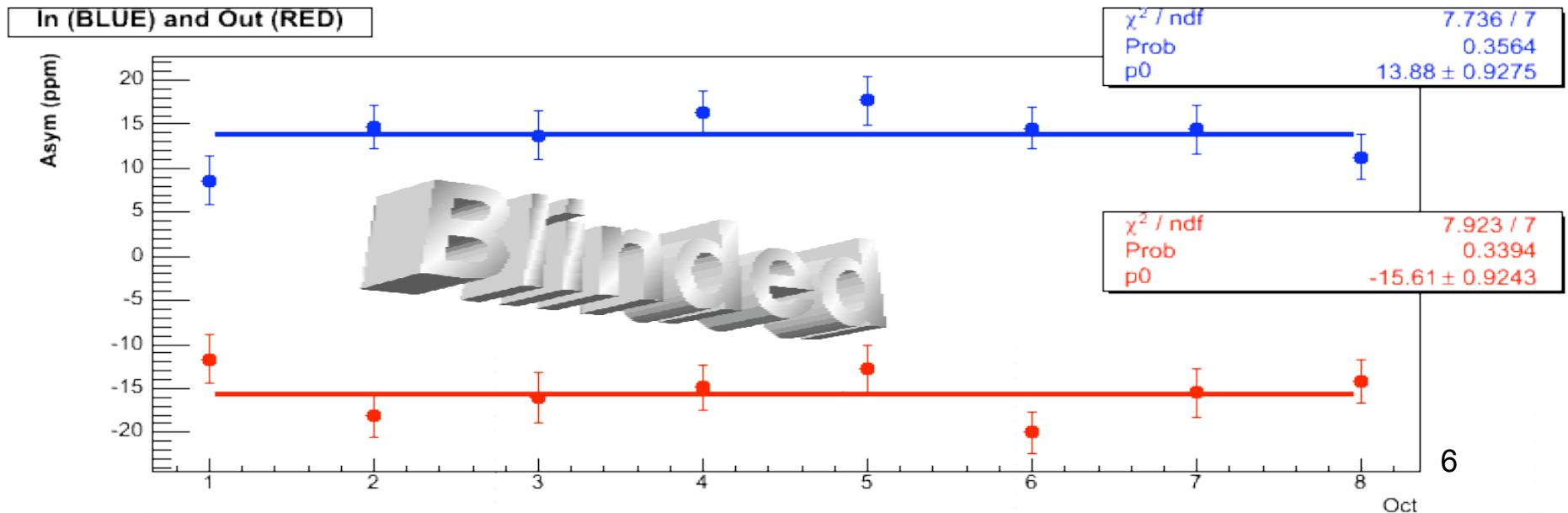
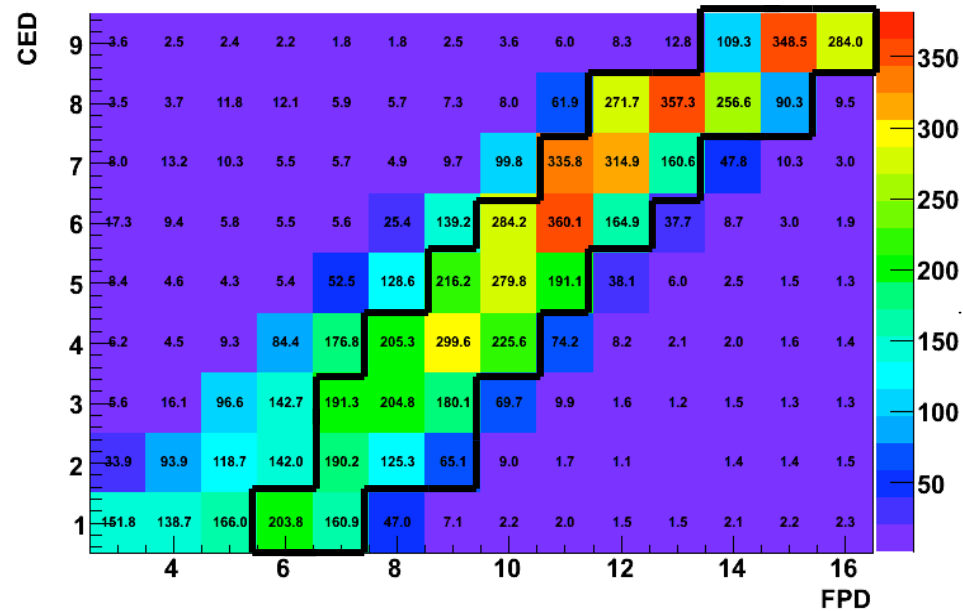
Uncorrected Yields  
and  
Blinded Asymmetries

# Preliminary Yields and Blinded Elastic Asymmetries

362MeV

LD2

70 C

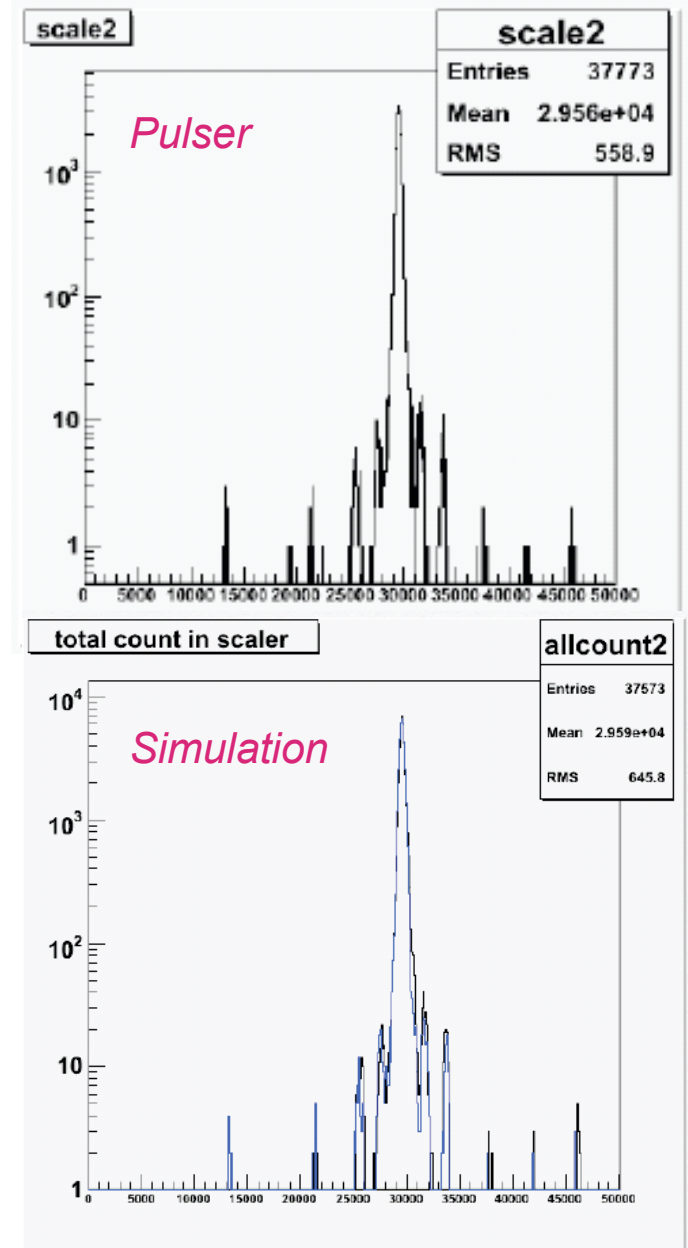


Pass 2

Scaler Counting Correction

# Scaler Counting Problem

- Electronics sorts detector coincidences ( $CED_i$  and  $FPD_j$ ) into separate scaler channels
  - FPGA-based system in North American electronics (4 octants)
- Because of error in FPGA programming, two short ( $\sim 3$  ns) pulses could be sent to scaler in  $< 7$  ns--problem for 140MHz scaler
  - Such a pulse pair could cause scaler to drop or add a random bit
- Problem blind to helicity
- $\sim 1\%$  of events have such miscounts
  - Problem pronounced in high-rate kinematics
- Preliminary assessment: effect on asymmetry is a small fraction of statistical uncertainty
  - Test by cutting data; compare with French octants
  - Confirmed by unchanged asymmetry after fix





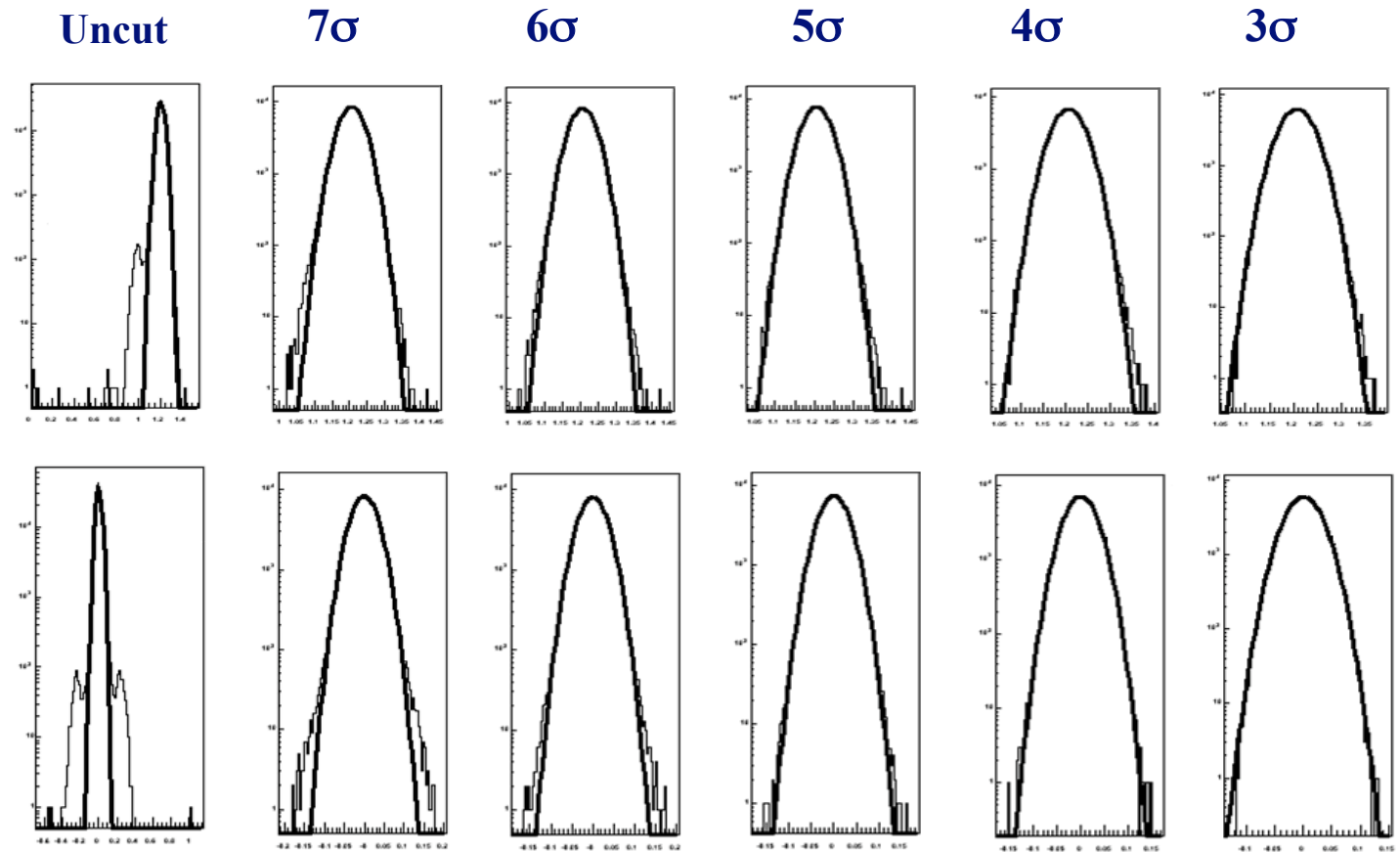
# Yield Cut/Asymmetry Effect

Coincidence cell CED9/FPD16, 15 runs chained

Cut on  
yield (per  
macropulse)

...

...effect on  
asymmetry



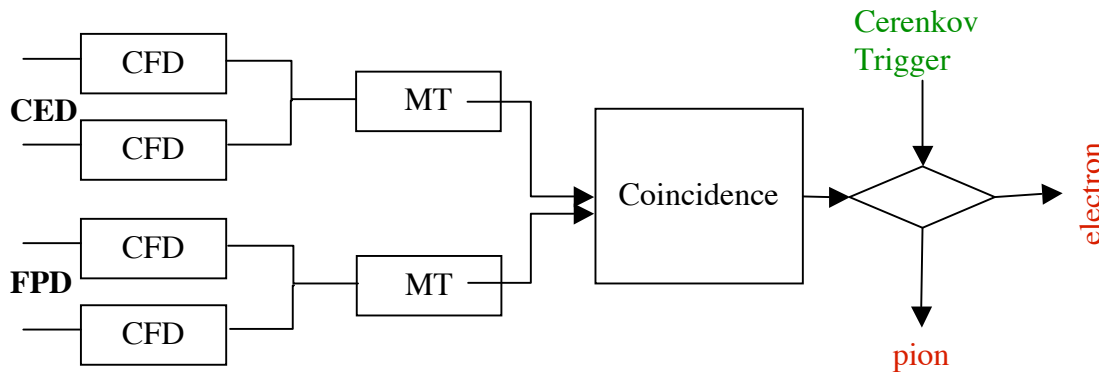
5 $\sigma$  cut removes  $\sim 1\%$  of our data for 362MeV LD2

Pass 3

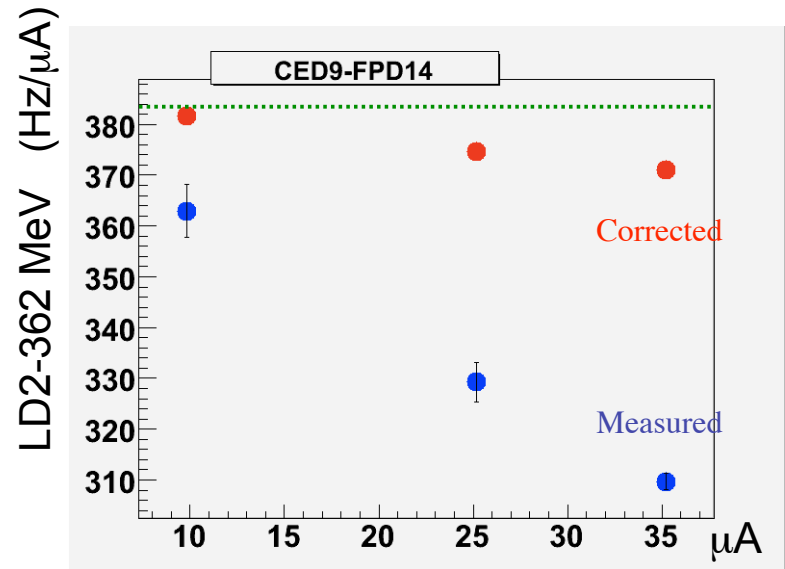
Electronics Corrections

# Electronics Corrections

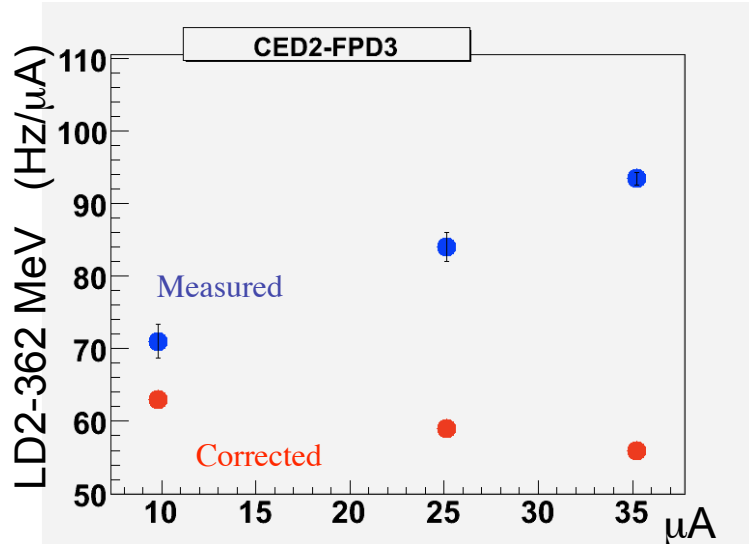
CED-FPD Coincidence Deadtime



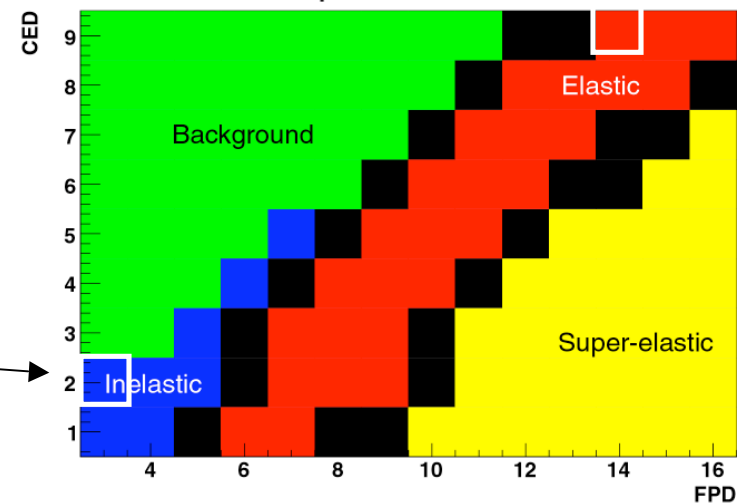
Electron Measured & Corrected Yields



Electron Measured & Corrected Yields



Matrix Space Cuts - 362 MeV

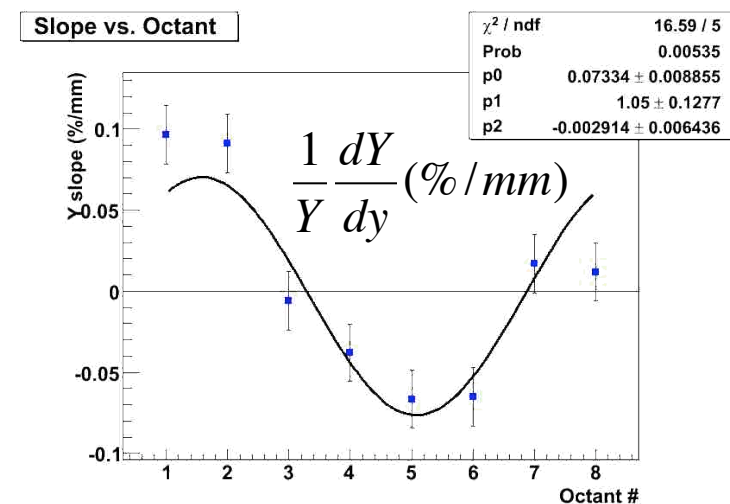
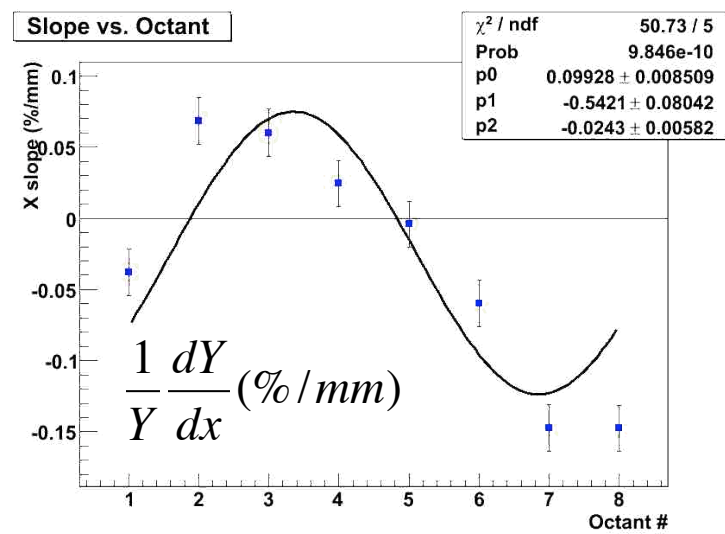


Pass 4

Helicity-Correlated Corrections

# Helicity-Correlated Beam Properties: Linear Regression

- Cross check slopes from natural beam motion with those from deliberate ‘coil-pulsing’ runs
- Sensitivities to helicity-correlated beam motion smaller at backward angles (data and simulation)

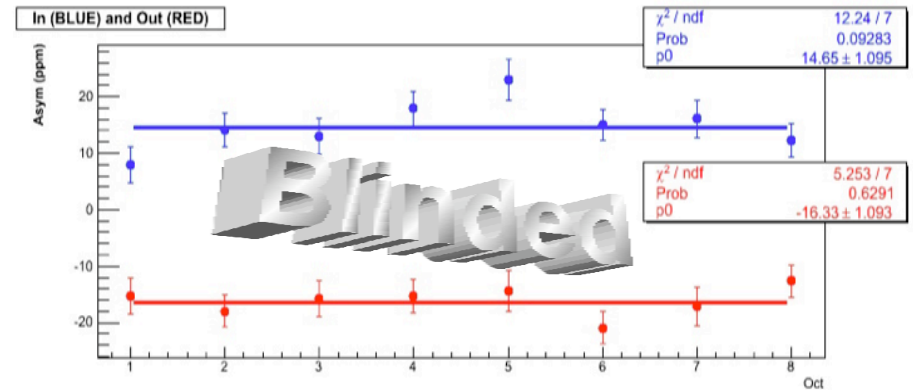
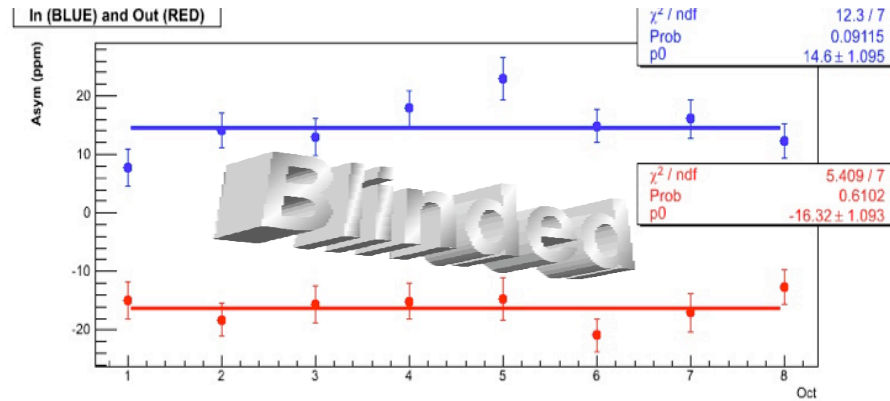
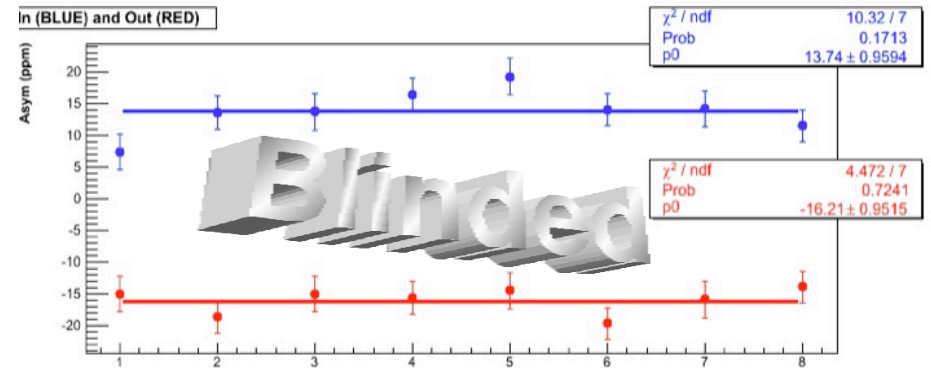
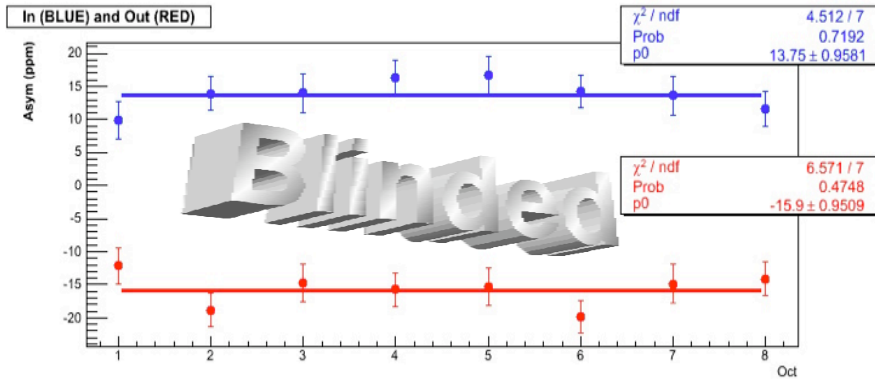


# Linear Regression Summary

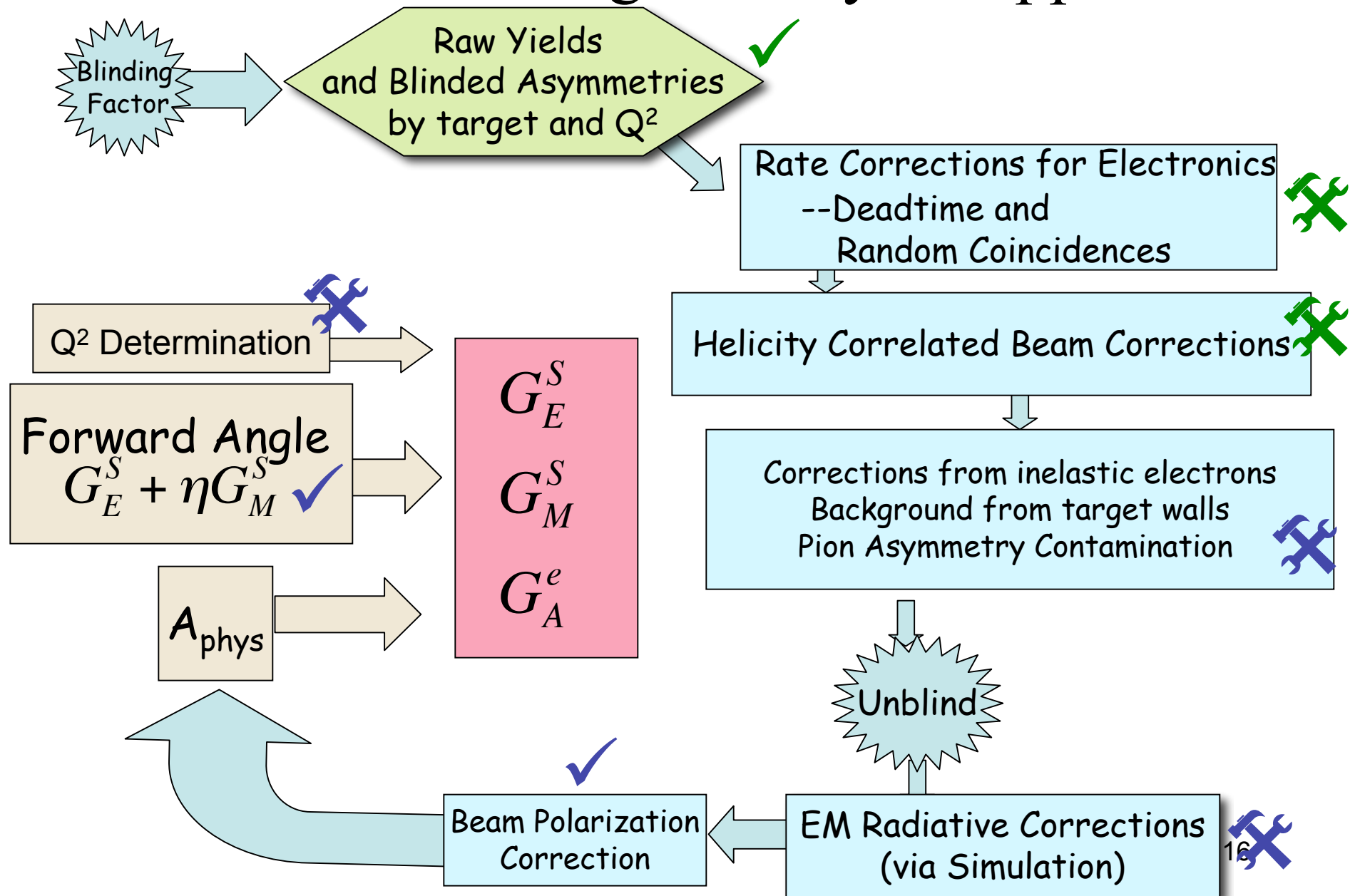
- Elastic Electron False Asymmetries

	Pass 3	Pass 4
q (ppb)	$-0.42 \pm 0.46$	$< 0.0069$
X (ppb)	$0.5 \pm 2.1$	$< 0.063$
Y (ppb)	$0.5 \pm 3.5$	$< 0.26$

# Four Pass Asymmetries



# G0 Backward Angle Analysis Approach





“The strangeness will wear off  
and I think we will discover the  
deeper meanings...”

*-Jackson Pollock*

# Backup Slides

# Induced Asymmetry Analysis :

$$A_{\text{det}} = A_{\text{true}} + A_{\text{false}} \quad A_{\text{det}} \text{ VS } A_I$$

Independent of  $A_I$

Electronics related part strongly dependent of  $A_I$

Total False Asymmetry related to the Global Dead Time correction:

$$\begin{aligned} A_{\text{false}} = & f_{\text{rand}} \left[ -A_{\tilde{r}_{\text{coinc}}} + A_I + A_{\tilde{r}_{\text{ced}}} + A_{\tilde{r}_{\text{fpd}}} \right] \\ & - DT_{\tilde{r}_{\text{ced}}^{\text{Single}}} \left[ A_{\tilde{r}_{\text{ced}}^{\text{Left}}} + A_I \right] - DT_{\tilde{r}_{\text{fpd}}^{\text{Single}}} \left[ A_{\tilde{r}_{\text{fpd}}^{\text{Left}}} + A_I \right] \\ & - DT_{\tilde{r}_{\text{ced}}^{\text{Single}}} \left[ A_{\tilde{r}_{\text{ced}}^{\text{Right}}} + A_I \right] - DT_{\tilde{r}_{\text{fpd}}^{\text{Single}}} \left[ A_{\tilde{r}_{\text{fpd}}^{\text{Right}}} + A_I \right] \\ & - DT_{\tilde{r}_{\text{ced}}^{\text{MT}}} \left[ A_{\tilde{r}_{\text{ced}}^{\text{MT}}} + A_I \right] - DT_{\tilde{r}_{\text{fpd}}^{\text{MT}}} \left[ A_{\tilde{r}_{\text{fpd}}^{\text{MT}}} + A_I \right] - DT_{\text{trigger}} \left[ A_{\tilde{r}_{\text{coinc}}^{\text{all}}} + A_I \right] \\ & - MH_{12} \left[ +A_I - A_{\tilde{r}_{\text{ced}}^{\text{all}}} + A_{\tilde{r}_{\text{fpd}}^{\text{all}}} \right] - MH_{12} \left[ +A_I - A_{\tilde{r}_{\text{coinc}}^{\text{other}}} \right] \end{aligned}$$

where :

- $f_{\text{rand}}$  is the fraction of CEDxFPD random coincidences
- $DT$  is the probability of dead time associated with each dead time source, *i.e* left and right singles, mean timers, and trigger
- $MH$  is the probability of having a multihit
- $\tilde{r}$  is the normalized rate of resp. coincidences, CED's CFD+MT and FPD's CFD+MT.